Application/Control No.	Applicant(s)/Patent under Reexamination	
10/623,569	MIYANO ET AL.	
Examiner	Art Unit	
Anish Desai	1771	

	SEARCHED			
Class	Subclass	Date	Examiner	
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INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
Inventor search using EAST	4/23/2007	APD	
428/354 (text search only)	4/23/2007	APD	
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